

IIT Bombay Nanofabrication Facility Dept of Electrical Engg, Annexe IIT Bombay, Powai, Mumbai - 400076 (022)25764435



Note: Device contact size >30  $\mu$ m. PDCS uses separate Force and Sense probes. Thus, 2-terminal measurements require 4 probes. Higher chance of metal scratching.

User Information
Name of the user:
Email:
Phone Number:
Faculty/ Guide Name:
Faculty/ Guide Email:
Name of the Department:
Sample Information Substrate:
Substrate Size:
Device Contact Size:
Measurements Information
Type of measurement (I-V/ C-V):
Temperature for measurement (RT/ Higher in °C):
Maximum measurement voltage (Expected):
Sample Processing (For Fabrication) Was the sample processed outside IITBNF?
□ Yes □ No
Any sample processed at any labs outside IITBNF at any intermediate process step is considered as 'sample processed outside IITBNF'

## Sample History \*

Step	Process	Equipment Used	Equipment Category (Clean, Semi Clean, etc.)	Location of Equipment (Lab Name)	Cleanliness of Lab

	l l			1
Number of Samp	les:			
			oles:	<u>—</u>
Preferred Slots (E	xpected Week): _			
Process Descrip	ption in detail *	:		
				<del></del>

We agree to acknowledge the Power Device characterization system (PDCS) at IITBNF, Dept of Electrical Engineering, Central Facility of IIT Bombay in our Publications/Reports/Thesis in which the data is used